

Search Notes



Application/Control No.

10/789,150

Examiner

George D. Spisich

Applicant(s)/Patent under Reexamination

CHUAN, CHEN WEN

Art Unit

3616

SEARCHED

Class	Subclass	Date	Examiner
180	41	10/6/05	YHJ
	907		
	326		
	282		
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updated above search		3/2/06	YHJ
180	8.2	3/2/06	
280	6.154		
	5.2		
	5.28		
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INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Consulted of Exr K. Hurley (180 + 280)	3/2/06	YHJ